Compa		National Semiconductor		3邦 专业PCB打样工厂,24小时加急出货 URL for Additional Information			
National Semi	iconductor	The Sight & Sound of Information	http://ww	w.national.com/	vw.national.com/quality/green/		
Contact Gloria Gordon	Engineeri	Title ng Project Manager	Phone 1-408-721-8435	Email Green.project@nsc.com			
Part Num	ber	MSL Rating	Peak Body Temp C	MaxTime (Sec)	Cycles		
TP3054WMX		4	220	30	4	-	
Document Date		I(Pb) and is NOT Europ		Weight (mg)	Unit Type	349	
1-Sep-2007		NOT China RoHS Co	mpliant	420.000	Each	.CO.M	
		Material Composit			1		
Item	Weight (mg)	Component	CAS#	Weight (mg)	Item-ppm	Part-ppr	
Plastic	305.050	Epoxy Resin	60676-86-0 25928-94-3	211.278 85.414	692,600 280,000	503,0 203,3	
		Sb2O3	1309-64-4	6.101	20,000	200,0	
		Brominated Epoxy	40039-93-8	2.257	20,000 7,400	14,:	
Leadframe	101.910	Cu	7440-50-8		974,500	236,4	
Leauname	101.910			99.311			
		Fe	7439-89-6	2.446	24,000	5,8	
		Zn	7440-66-6	0.122	1,200	LECO	
		P	7723-14-0	0.031	300	317	
Ext. LeadFinish	6.350		7440-31-5	5.398	850,000	12,8	
		Pb	7439-92-1	0.953	150,000	2,	
Chip	5.350	Si	7440-21-3	5.318	994,000	12,	
		AI	7429-90-5	0.032	6,000		
Die Attach	0.570	Ag	7440-22-4	0.428	750,000	1,	
		Epoxy Resin	25928-94-3	0.143	250,000	:	
Int. LeadFinish	0.470		7440-22-4		1.000.000	1.	
Additionally, the following 1. One or more dopan	g should be noted: ht materials may be	Ag	ub-ppm levels to provide se	0.470 0.300 only. It has not been v miconductor propertie	es.		
Wires Note: The device conten Additionally, the following 1. One or more dopan	0.300 t disclosed herewit g should be noted: t materials may be	Ag Au h is approximate and is based present in the silicon die at si	7440-57-5 d on engineering estimates of ub-ppm levels to provide se he specific compound used	0.470 0.300 only. It has not been v miconductor propertie , which is considered	1,000,000 verified through ar	1, nalytical test	
Wires Note: The device conten Additionally, the following 1. One or more dopan	0.300 ht disclosed herewit g should be noted: ht materials may be onents listed are gen RoHS Definiti Chromium, Po	Ag Au h is approximate and is based present in the silicon die at si heric and may or may not be t <b>ROHS Material CC</b> on: Quantity limit of 0.1% by r olybrominated Biphenyls (PBE	7440-57-5 d on engineering estimates of ub-ppm levels to provide se he specific compound used <b>pmposition Decla</b> mass (1000 PPM) in homog 3), Polybrominated Dipheny	0.470 0.300 only. It has not been w miconductor propertie , which is considered wration	1,000,000 verified through an es. I proprietary. Lead (Pb), Mercu	nalytical test	
Wires Note: The device conten Additionally, the following 1. One or more dopan 2. Epoxy resin compo RoHS Directive 2002/95/EC Subject to the limitations	0.300 tt disclosed herewitt g should be noted: tt materials may be nents listed are gen RoHS Definiti Chromium, Pr (100 PPM) of s below, National S	Ag Au h is approximate and is based present in the silicon die at si heric and may or may not be the <b>ROHS Material CC</b> on: Quantity limit of 0.1% by rolybrominated Biphenyls (PBE homogeneous material for Ca emiconductor Corporation ("N	7440-57-5 d on engineering estimates of ub-ppm levels to provide se he specific compound used <b>pmposition Decla</b> mass (1000 PPM) in homog 3), Polybrominated Dipheny dmium ational") certifies the following	0.470 0.300 only. It has not been w miconductor propertie , which is considered wration geneous material for: I t Ethers (PBDE) and ng information as of th	1,000,000 verified through an es. proprietary. Lead (Pb), Mercu quantity limit of C	nalytical tes Iry, Hexaval .01% by m	
Wires Note: The device conten Additionally, the following 1. One or more dopan 2. Epoxy resin compo RoHS Directive 2002/95/EC Subject to the limitations 1. National products w 2002/95/EC ("RoHS") threshold levels, excep 2. National products w not contain other RoH solder and RoHS exer 3. National products a Materials and Product www.national.com/qu	0.300 tt disclosed herewit g should be noted: tt materials may be inents listed are gen RoHS Definiti Chromium, P- (100 PPM) of s below, National S with lead-free solder . These products d pt lead in RoHS ex- with lead-containing IS restricted substa mpt applications 5, are manufactured in ts and (SC) CSP-9- tality/green/. do not contain and a	Ag Au h is approximate and is based present in the silicon die at sineric and may or may not be t <b>ROHS Material CC</b> on: Quantity limit of 0.1% by r olybrominated Biphenyls (PBE homogeneous material for Ca emiconductor Corporation ("N comply with the European U o not contain homogeneous m empt applications 5, 7a and 7 isolder do not comply with Ro nces or homogeneous materia 7a and 7c. conformance with National si 111S2 National's List of Banr are not manufactured with ozo	7440-57-5 d on engineering estimates of ub-ppm levels to provide set he specific compound used <b>pmposition Decla</b> mass (1000 PPM) in homog 3), Polybrominated Dipheny dmium ational") certifies the followin nion's Directive on the Rest haterials with Joint Industry c. JHS, because they contain I als with JIG-101 Level A ma pecifications (SC) CSP-9-1° hed and Reportable Substar	0.470 0.300 only. It has not been we miconductor propertie which is considered <b>tration</b> peneous material for: If theres (PBDE) and ing information as of the riction of the Use of H Guide (JIG) -101 Lew ead in a non-exempt aterials above Level A 11C1 Supplier Enviro nees, which are availa	1,000,000 verified through an es. proprietary. Lead (Pb), Mercu quantity limit of C he document date lazardous Substa vel A materials ab application. Thes threshold levels, nmental Requirer ble at	nalytical tes iry, Hexaval 0.01% by m e. ances pove Level A se products , except lea ments for	

Banned Substance Monitori						
Part Number	Document Date					
TP3054WMX						

#### Contains Lead(Pb) and is NOT European RoHS Compliant.

#### NOT China RoHS Compliant

Use	Material	Cd	CrVI	Pb	Hg	PBB	PBDE	Ref #
Device	CHIP	<1	<1	<1	<1	<1	<1	1000
	COMPOUND	<2	<2	<2	<2	<100	<100	564
	EPOXY	<2	<5	<5	<1	<10	<10	32
	EXTLF	<2	<2	149000	<2	NA	NA	56
	FRAME	<2	<2	<2	<2	NA	NA	51
	WIRE	<2	<5	<5	<1	<10	<10	75

\* Cd: Cadmium, CrVI: Hexavalent Chromium, Pb: Lead, Hg: Mercury, ND: Not Detected \* Unless otherwise noted, units are in PPM (parts-per-million)

Ref #	3rd Party Analysis (available upon request, subject to a non-disclosure agreement)
1000	Analysis on 04/17/2007 by Balazs Analytical Services-Freemont CA per Report# 07-01051-07
32	Analysis on 05/16/2007 by ALS per Report# ATJB/3488BS/2007
51	Analysis on 03/13/2007 by SGS per Report# LPCI/05141/07
56	Analysis on 04/27/2007 by SGS per Report# LPCI/07440/07
75	Analysis on 05/16/2007 by ALS per Report# ATJB/3490BS/2007
564	Analysis on 04/27/2007 by SGS per Report# LPCI/07426/07



## 《电子信息产品污染控制管理办法》的声明

"Electronic Information Products Pollution Control Measures" Statement

#### China RoHS Declaration

产品名称	TP3054WMX
Product Name	

	 有毒有害物 <b>质或元素</b> Toxic and harmful substances or elements					
部件名称 Part	<b>铅</b> (Pb)	汞 (Hg)	<b>뗾</b> (Cd)	六价 <b>铬</b> (Cr6+)	多 <b>溴联苯</b> (PBB)	多 <b>溴二苯醚</b> (PBDE)
集成 <b>电路</b> Integrated Circuit	Х	0	0	0	0	0

### O:表示<mark>该有毒有害物质在该部件所有均质材料中的含量均在SJ/T 11363-2006</mark> 标准规定的限量要求以下。

**O** : Indicates that this hazardous substance contained in all homogeneous materials of this part is below the limit requirement in SJ/T 11363-2006.

#### X:表示该有毒有害物质至少在该部件的某一均质材料中的含量超出 SJ/T 11363-2006 标准规定的限量要求。

**X** : Indicates that this hazardous substance contained in at least one of the homogeneous materials of this part is above the limit requirement in SJ/T 11363-2006.

## 美国国家半**导体的产品不会含有镉、汞、六价铬、多溴联苯(PBB)** 和二苯**醚(PBDE)**。

National Semiconductor's products will not contain cadmium, mercury, hexavalent chromium, polybrominated biphenyls (PBBs) and diphenyl ether (PBDE).



# **环保使用期限(epup)** 是指以符号在这里展出. 环保使用期限(epup) 的有效期只有当产品使用范围以内的数据表中的规格.

The Environmental Protection Use Period (EPUP) is defined by the symbol shown here. The Environmental Protection Use Period (EPUP) is valid only when product is used within the limits of the data sheet specifications.